



ALPHA & OMEGA
SEMICONDUCTOR

AO3416

20V N-Channel MOSFET

General Description

The AO3416 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications. It is ESD protected.

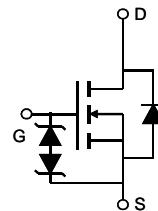
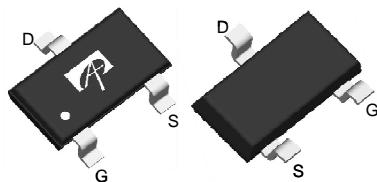
Product Summary

| | |
|------------------------------------|--------|
| V_{DS} | 20V |
| I_D (at $V_{GS}=4.5V$) | 6.5A |
| $R_{DS(ON)}$ (at $V_{GS}=4.5V$) | < 22mΩ |
| $R_{DS(ON)}$ (at $V_{GS} = 2.5V$) | < 26mΩ |
| $R_{DS(ON)}$ (at $V_{GS} = 1.8V$) | < 34mΩ |

ESD protected



SOT23
Top View Bottom View



Absolute Maximum Ratings $T_A=25^\circ\text{C}$ unless otherwise noted

| Parameter | Symbol | Maximum | Units |
|--|----------------|------------|-------|
| Drain-Source Voltage | V_{DS} | 20 | V |
| Gate-Source Voltage | V_{GS} | ± 8 | V |
| Continuous Drain Current | I_D | 6.5 | A |
| $T_A=70^\circ\text{C}$ | | 5.2 | |
| Pulsed Drain Current ^C | I_{DM} | 30 | W |
| $T_A=25^\circ\text{C}$ | P_D | 1.4 | |
| $T_A=70^\circ\text{C}$ | | 0.9 | |
| Junction and Storage Temperature Range | T_J, T_{STG} | -55 to 150 | °C |

Thermal Characteristics

| Parameter | Symbol | Typ | Max | Units |
|--|-----------------|-----|-----|-------|
| Maximum Junction-to-Ambient ^A $t \leq 10s$ | $R_{\theta JA}$ | 70 | 90 | °C/W |
| Maximum Junction-to-Ambient ^{A D} Steady-State | | 100 | 125 | °C/W |
| Maximum Junction-to-Lead | $R_{\theta JL}$ | 63 | 80 | °C/W |

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

| Symbol | Parameter | Conditions | Min | Typ | Max | Units |
|-----------------------------|---------------------------------------|---|-----|----------|----------|------------------|
| STATIC PARAMETERS | | | | | | |
| BV_{DSS} | Drain-Source Breakdown Voltage | $I_D=250\mu\text{A}, V_{GS}=0\text{V}$ | 20 | | | V |
| I_{DSS} | Zero Gate Voltage Drain Current | $V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$ | | | 1 5 | μA |
| I_{GSS} | Gate-Body leakage current | $V_{DS}=0\text{V}, V_{GS}=\pm 8\text{V}$ | | | ± 10 | μA |
| $V_{\text{GS(th)}}$ | Gate Threshold Voltage | $V_{DS}=V_{GS}, I_D=250\mu\text{A}$ | 0.4 | 0.7 | 1.1 | V |
| $I_{\text{D(ON)}}$ | On state drain current | $V_{GS}=4.5\text{V}, V_{DS}=5\text{V}$ | 30 | | | A |
| $R_{\text{DS(ON)}}$ | Static Drain-Source On-Resistance | $V_{GS}=4.5\text{V}, I_D=6.5\text{A}$ $T_J=125^\circ\text{C}$ | | 16 22 | 22 | $\text{m}\Omega$ |
| | | $V_{GS}=2.5\text{V}, I_D=5.5\text{A}$ | | 18 | 26 | $\text{m}\Omega$ |
| | | $V_{GS}=1.8\text{V}, I_D=5\text{A}$ | | 21 | 34 | $\text{m}\Omega$ |
| g_{FS} | Forward Transconductance | $V_{DS}=5\text{V}, I_D=6.5\text{A}$ | | 50 | | S |
| V_{SD} | Diode Forward Voltage | $I_S=1\text{A}, V_{GS}=0\text{V}$ | | 0.62 | 1 | V |
| I_S | Maximum Body-Diode Continuous Current | | | | 2 | A |
| DYNAMIC PARAMETERS | | | | | | |
| C_{iss} | Input Capacitance | $V_{GS}=0\text{V}, V_{DS}=10\text{V}, f=1\text{MHz}$ | | 1295 | 1650 | pF |
| C_{oss} | Output Capacitance | | | 160 | | pF |
| C_{rss} | Reverse Transfer Capacitance | | | 87 | | pF |
| R_g | Gate resistance | $V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$ | | 1.8 | | $\text{k}\Omega$ |
| SWITCHING PARAMETERS | | | | | | |
| Q_g | Total Gate Charge | $V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, I_D=6.5\text{A}$ | | 10 | | nC |
| Q_{gs} | Gate Source Charge | | | 4.2 | | nC |
| Q_{gd} | Gate Drain Charge | | | 2.6 | | nC |
| $t_{\text{D(on)}}$ | Turn-On Delay Time | $V_{GS}=4.5\text{V}, V_{DS}=10\text{V}, R_L=1.54\Omega, R_{\text{GEN}}=3\Omega$ | | 280 | | ns |
| t_r | Turn-On Rise Time | | | 328 | | ns |
| $t_{\text{D(off)}}$ | Turn-Off Delay Time | | | 3.76 | | us |
| t_f | Turn-Off Fall Time | | | 2.24 | | us |
| t_{rr} | Body Diode Reverse Recovery Time | $I_F=6.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 31 | 41 | ns |
| Q_{rr} | Body Diode Reverse Recovery Charge | $I_F=6.5\text{A}, dI/dt=100\text{A}/\mu\text{s}$ | | 6.8 | | nC |

A. The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using $\leq 10\text{s}$ junction-to-ambient thermal resistance.

C. Repetitive rating, pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$. Ratings are based on low frequency and duty cycles to keep initial $T_J=25^\circ\text{C}$.

D. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to lead $R_{\theta JL}$ and lead to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-ambient thermal impedance which is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

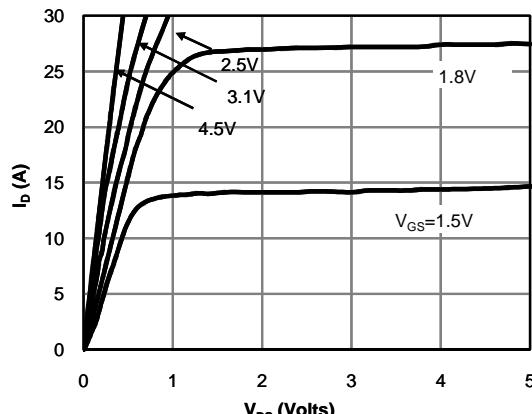


Fig 1: On-Region Characteristics (Note E)

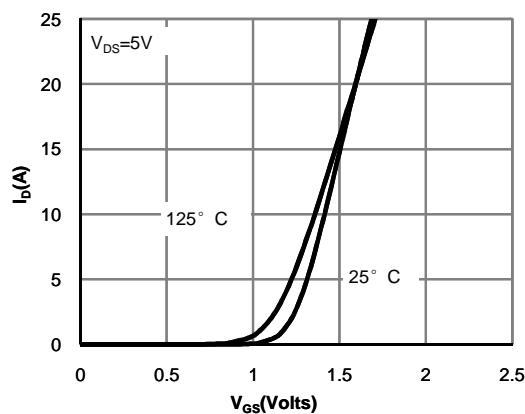


Figure 2: Transfer Characteristics (Note E)

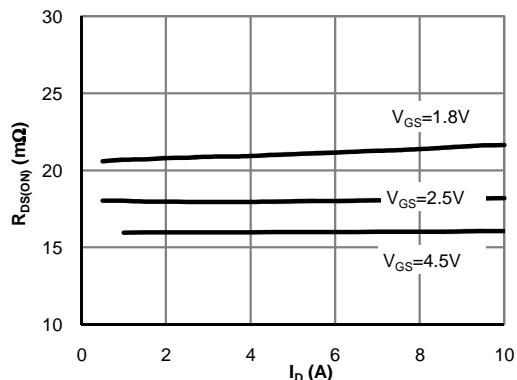


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

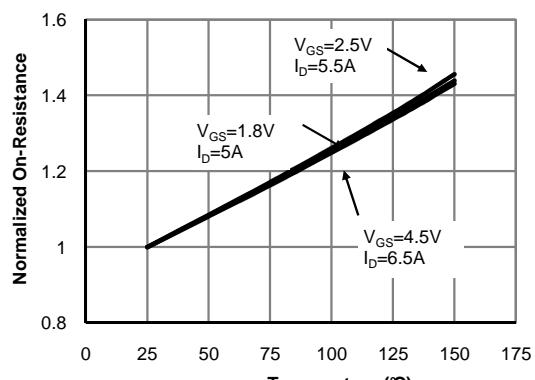


Figure 4: On-Resistance vs. Junction Temperature (Note E)

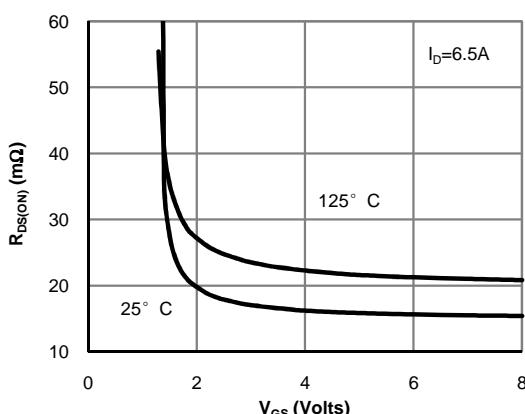


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

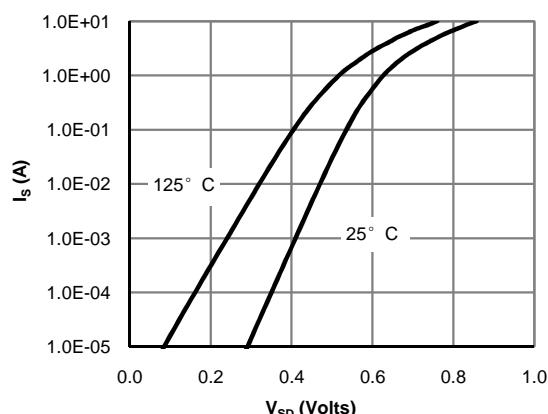
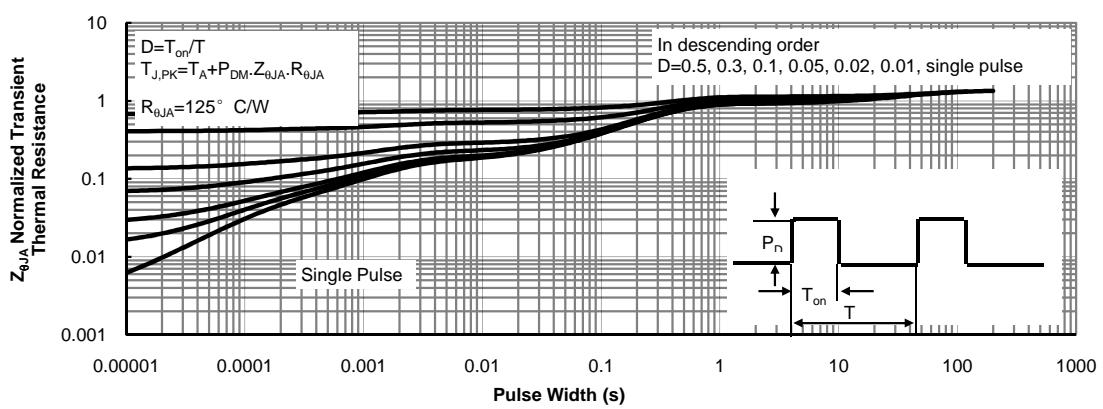
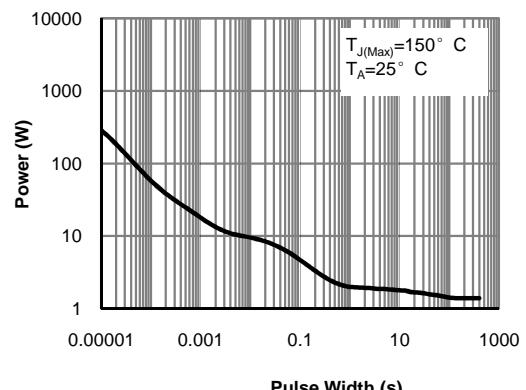
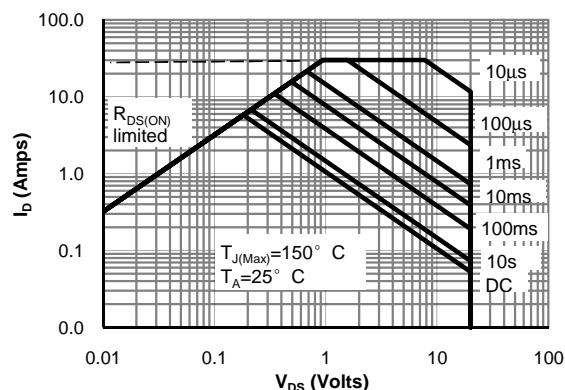
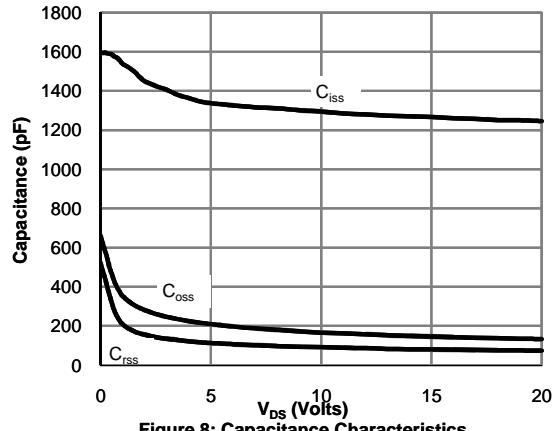
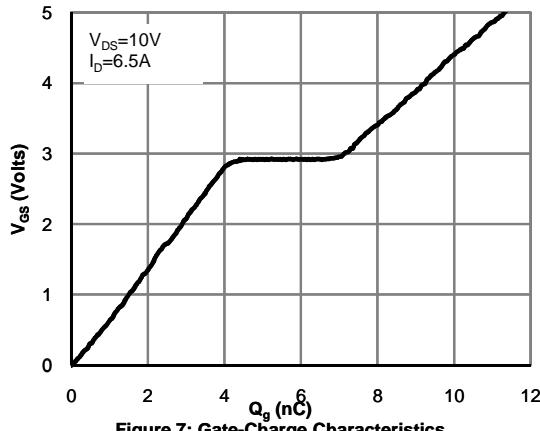
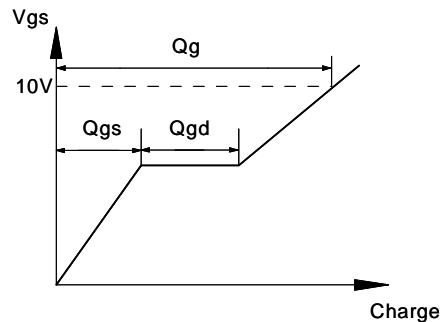
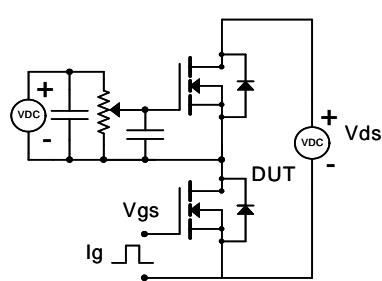
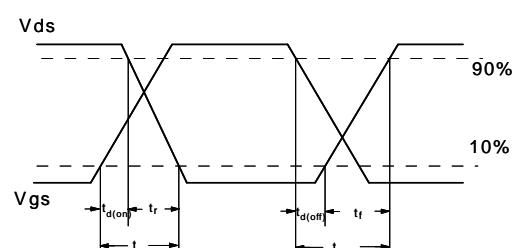
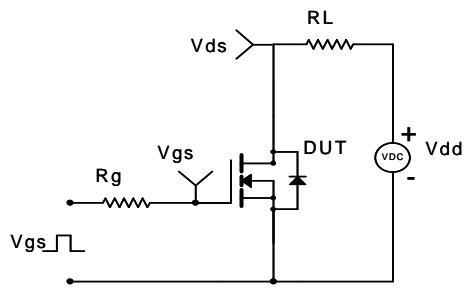


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Gate Charge Test Circuit & Waveform

Resistive Switching Test Circuit & Waveforms

Diode Recovery Test Circuit & Waveforms
